


<b>Search Notes</b> 	<b>Application/Control No.</b> 10576850	<b>Applicant(s)/Patent Under Reexamination</b> PARK ET AL.
	<b>Examiner</b> John P Sheehan	<b>Art Unit</b> 1793

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES			
Search Notes		Date	Examiner
EAST Search		12/18/2009	JPS

INTERFERENCE SEARCH			
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